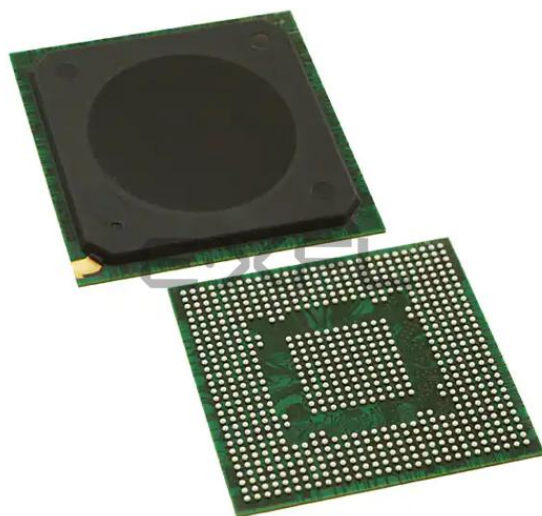




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Understanding [Embedded - Microprocessors](#)

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of [Embedded - Microprocessors](#)

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

Product Status	Obsolete
Core Processor	PowerPC e500
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	1.2GHz
Co-Processors/DSP	Signal Processing; SPE, Security; SEC
RAM Controllers	DDR, DDR2, SDRAM
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (4)
SATA	-
USB	-
Voltage - I/O	1.8V, 2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	Cryptography, Random Number Generator
Package / Case	689-BBGA Exposed Pad
Supplier Device Package	689-TEPBGA II (31x31)
Purchase URL	https://www.e-xfl.com/pro/item?MUrl=&PartUrl=mpc8545epxatgb

- AESU—Advanced Encryption Standard unit
 - Implements the Rijndael symmetric key cipher
 - ECB, CBC, CTR, and CCM modes
 - 128-, 192-, and 256-bit key lengths
- AFEU—ARC four execution unit
 - Implements a stream cipher compatible with the RC4 algorithm
 - 40- to 128-bit programmable key
- MDEU—message digest execution unit
 - SHA with 160- or 256-bit message digest
 - MD5 with 128-bit message digest
 - HMAC with either algorithm
- KEU—Kasumi execution unit
 - Implements F8 algorithm for encryption and F9 algorithm for integrity checking
 - Also supports A5/3 and GEA-3 algorithms
- RNG—random number generator
- XOR engine for parity checking in RAID storage applications
- Dual I²C controllers
 - Two-wire interface
 - Multiple master support
 - Master or slave I²C mode support
 - On-chip digital filtering rejects spikes on the bus
- Boot sequencer
 - Optionally loads configuration data from serial ROM at reset via the I²C interface
 - Can be used to initialize configuration registers and/or memory
 - Supports extended I²C addressing mode
 - Data integrity checked with preamble signature and CRC
- DUART
 - Two 4-wire interfaces (SIN, SOUT, $\overline{\text{RTS}}$, $\overline{\text{CTS}}$)
 - Programming model compatible with the original 16450 UART and the PC16550D
- Local bus controller (LBC)
 - Multiplexed 32-bit address and data bus operating at up to 133 MHz
 - Eight chip selects support eight external slaves
 - Up to eight-beat burst transfers
 - The 32-, 16-, and 8-bit port sizes are controlled by an on-chip memory controller.
 - Three protocol engines available on a per chip select basis:
 - General-purpose chip select machine (GPCM)
 - Three user programmable machines (UPMs)

4.3 eTSEC Gigabit Reference Clock Timing

The following table provides the eTSEC gigabit reference clocks (EC_GTX_CLK125) AC timing specifications for the device.

Table 6. EC_GTX_CLK125 AC Timing Specifications

Parameter/Condition	Symbol	Min	Typ	Max	Unit	Notes
EC_GTX_CLK125 frequency	f_{G125}	—	125	—	MHz	—
EC_GTX_CLK125 cycle time	t_{G125}	—	8	—	ns	
EC_GTX_CLK125 rise and fall time L/TVDD = 2.5 V L/TVDD = 3.3 V	t_{G125R}, t_{G125F}	—	—	0.75 1.0	ns	1
EC_GTX_CLK125 duty cycle GMII, TBI 1000Base-T for RGMII, RTBI	t_{G125H}/t_{G125L}	45 47	—	55 53	%	2, 3

Notes:

1. Rise and fall times for EC_GTX_CLK125 are measured from 0.5 and 2.0 V for L/TV_{DD} = 2.5 V, and from 0.6 and 2.7 V for L/TV_{DD} = 3.3 V.
2. Timing is guaranteed by design and characterization.
3. EC_GTX_CLK125 is used to generate the GTX clock TSEC_n_GTX_CLK for the eTSEC transmitter with 2% degradation. EC_GTX_CLK125 duty cycle can be loosened from 47/53% as long as the PHY device can tolerate the duty cycle generated by the TSEC_n_GTX_CLK. See [Section 8.2.6, "RGMII and RTBI AC Timing Specifications,"](#) for duty cycle for 10Base-T and 100Base-T reference clock.

4.4 PCI/PCI-X Reference Clock Timing

When the PCI/PCI-X controller is configured for asynchronous operation, the reference clock for the PCI/PCI-x controller is not the SYCLK input, but instead the PCIn_CLK. The following table provides the PCI/PCI-X reference clock AC timing specifications for the device.

Table 7. PCIn_CLK AC Timing Specifications

At recommended operating conditions (see [Table 2](#)) with OV_{DD} = 3.3 V ± 165 mV.

Parameter/Condition	Symbol	Min	Typ	Max	Unit	Notes
PCIn_CLK frequency	f_{PCICLK}	16	—	133	MHz	—
PCIn_CLK cycle time	t_{PCICLK}	7.5	—	60	ns	—
PCIn_CLK rise and fall time	t_{PCIKH}, t_{PCIKL}	0.6	1.0	2.1	ns	1, 2
PCIn_CLK duty cycle	$t_{PCIKHKL}/t_{PCICLK}$	40	—	60	%	2

Notes:

1. Rise and fall times for SYCLK are measured at 0.6 and 2.7 V.
2. Timing is guaranteed by design and characterization.

Figure 13 shows the MII receive AC timing diagram.

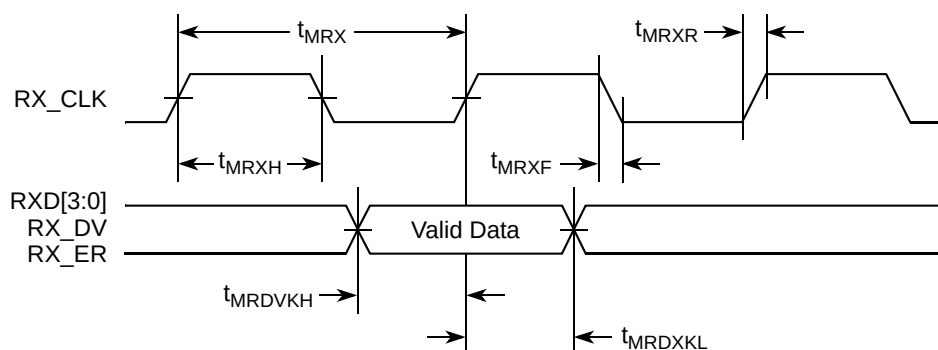


Figure 13. MII Receive AC Timing Diagram

8.2.4 TBI AC Timing Specifications

This section describes the TBI transmit and receive AC timing specifications.

8.2.4.1 TBI Transmit AC Timing Specifications

This table provides the TBI transmit AC timing specifications.

Table 30. TBI Transmit AC Timing Specifications

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit
TCG[9:0] setup time GTX_CLK going high	t_{TTKHDV}	2.0	—	—	ns
TCG[9:0] hold time from GTX_CLK going high	t_{TTKHDX}	1.0	—	—	ns
GTX_CLK rise (20%–80%)	t_{TTXR}^2	—	—	1.0	ns
GTX_CLK fall time (80%–20%)	t_{TTXF}^2	—	—	1.0	ns

Notes:

- The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{TTKHDV} symbolizes the TBI transmit timing (TT) with respect to the time from t_{TTX} (K) going high (H) until the referenced data signals (D) reach the valid state (V) or setup time. Also, t_{TTKHDX} symbolizes the TBI transmit timing (TT) with respect to the time from t_{TTX} (K) going high (H) until the referenced data signals (D) reach the invalid state (X) or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{TTX} represents the TBI (T) transmit (TX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
- Guaranteed by design.

10.2 Local Bus AC Electrical Specifications

This table describes the timing parameters of the local bus interface at $BV_{DD} = 3.3$ V. For information about the frequency range of local bus, see [Section 20.1, “Clock Ranges.”](#)

Table 40. Local Bus Timing Parameters ($BV_{DD} = 3.3$ V)—PLL Enabled

Parameter	Symbol ¹	Min	Max	Unit	Notes
Local bus cycle time	t_{LBK}	7.5	12	ns	2
Local bus duty cycle	t_{LBKH}/t_{LBK}	43	57	%	—
LCLK[n] skew to LCLK[m] or LSYNC_OUT	$t_{LBKSKEW}$	—	150	ps	7, 8
Input setup to local bus clock (except $\overline{LGTA}/LUPWAIT$)	$t_{LBIVKH1}$	1.8	—	ns	3, 4
$\overline{LGTA}/LUPWAIT$ input setup to local bus clock	$t_{LBIVKH2}$	1.7	—	ns	3, 4
Input hold from local bus clock (except $\overline{LGTA}/LUPWAIT$)	$t_{LBIXKH1}$	1.0	—	ns	3, 4
$\overline{LGTA}/LUPWAIT$ input hold from local bus clock	$t_{LBIXKH2}$	1.0	—	ns	3, 4
LALE output transition to LAD/LDP output transition (LATCH hold time)	t_{LBOTOT}	1.5	—	ns	6
Local bus clock to output valid (except LAD/LDP and LALE)	$t_{LBKHOV1}$	—	2.0	ns	—
Local bus clock to data valid for LAD/LDP	$t_{LBKHOV2}$	—	2.2	ns	3
Local bus clock to address valid for LAD	$t_{LBKHOV3}$	—	2.3	ns	3
Local bus clock to LALE assertion	$t_{LBKHOV4}$	—	2.3	ns	3
Output hold from local bus clock (except LAD/LDP and LALE)	$t_{LBKHOX1}$	0.7	—	ns	3
Output hold from local bus clock for LAD/LDP	$t_{LBKHOX2}$	0.7	—	ns	3
Local bus clock to output high Impedance (except LAD/LDP and LALE)	$t_{LBKHOZ1}$	—	2.5	ns	5
Local bus clock to output high impedance for LAD/LDP	$t_{LBKHOZ2}$	—	2.5	ns	5

Notes:

1. The symbols used for timing specifications follow the pattern of $t_{(\text{first two letters of functional block})(\text{signal})(\text{state})(\text{reference})(\text{state})}$ for inputs and $t_{(\text{first two letters of functional block})(\text{reference})(\text{state})(\text{signal})(\text{state})}$ for outputs. For example, $t_{LBIXKH1}$ symbolizes local bus timing (LB) for the input (I) to go invalid (X) with respect to the time the t_{LBK} clock reference (K) goes high (H), in this case for clock one (1). Also, t_{LBKHOX} symbolizes local bus timing (LB) for the t_{LBK} clock reference (K) to go high (H), with respect to the output (O) going invalid (X) or output hold time.
2. All timings are in reference to LSYNC_IN for PLL enabled and internal local bus clock for PLL bypass mode.
3. All signals are measured from $BV_{DD}/2$ of the rising edge of LSYNC_IN for PLL enabled or internal local bus clock for PLL bypass mode to $0.4 \times BV_{DD}$ of the signal in question for 3.3-V signaling levels.
4. Input timings are measured at the pin.
5. For purposes of active/float timing measurements, the Hi-Z or off state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.
6. t_{LBOTOT} is a measurement of the minimum time between the negation of LALE and any change in LAD. t_{LBOTOT} is programmed with the LBCR[AHD] parameter.
7. Maximum possible clock skew between a clock LCLK[m] and a relative clock LCLK[n]. Skew measured between complementary signals at $BV_{DD}/2$.
8. Guaranteed by design.

Table 42. Local Bus Timing Parameters—PLL Bypassed (continued)

Parameter	Symbol ¹	Min	Max	Unit	Notes
LGTA/LUPWAIT input hold from local bus clock	$t_{LBIXKL2}$	-1.3	—	ns	4, 5
LALE output transition to LAD/LDP output transition (LATCH hold time)	t_{LBOTOT}	1.5	—	ns	6
Local bus clock to output valid (except LAD/LDP and LALE)	$t_{LBKLOV1}$	—	-0.3	ns	—
Local bus clock to data valid for LAD/LDP	$t_{LBKLOV2}$	—	-0.1	ns	4
Local bus clock to address valid for LAD	$t_{LBKLOV3}$	—	0	ns	4
Local bus clock to LALE assertion	$t_{LBKLOV4}$	—	0	ns	4
Output hold from local bus clock (except LAD/LDP and LALE)	$t_{LBKLOX1}$	-3.7	—	ns	4
Output hold from local bus clock for LAD/LDP	$t_{LBKLOX2}$	-3.7	—	ns	4
Local bus clock to output high Impedance (except LAD/LDP and LALE)	$t_{LBKLOZ1}$	—	0.2	ns	7
Local bus clock to output high impedance for LAD/LDP	$t_{LBKLOZ2}$	—	0.2	ns	7

Notes:

1. The symbols used for timing specifications follow the pattern of $t_{(\text{first two letters of functional block})(\text{signal})(\text{state})(\text{reference})(\text{state})}$ for inputs and $t_{(\text{first two letters of functional block})(\text{reference})(\text{state})(\text{signal})(\text{state})}$ for outputs. For example, $t_{LBIXKH1}$ symbolizes local bus timing (LB) for the input (I) to go invalid (X) with respect to the time the t_{LBK} clock reference (K) goes high (H), in this case for clock one (1). Also, t_{LBKHGX} symbolizes local bus timing (LB) for the t_{LBK} clock reference (K) to go high (H), with respect to the output (O) going invalid (X) or output hold time.
2. All timings are in reference to local bus clock for PLL bypass mode. Timings may be negative with respect to the local bus clock because the actual launch and capture of signals is done with the internal launch/capture clock, which precedes LCLK by t_{LBKHKT} .
3. Maximum possible clock skew between a clock LCLK[m] and a relative clock LCLK[n]. Skew measured between complementary signals at $BV_{DD}/2$.
4. All signals are measured from $BV_{DD}/2$ of the rising edge of local bus clock for PLL bypass mode to $0.4 \times BV_{DD}$ of the signal in question for 3.3-V signaling levels.
5. Input timings are measured at the pin.
6. The value of t_{LBOTOT} is the measurement of the minimum time between the negation of LALE and any change in LAD.
7. For purposes of active/float timing measurements, the Hi-Z or off state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.
8. Guaranteed by characterization.
9. Guaranteed by design.

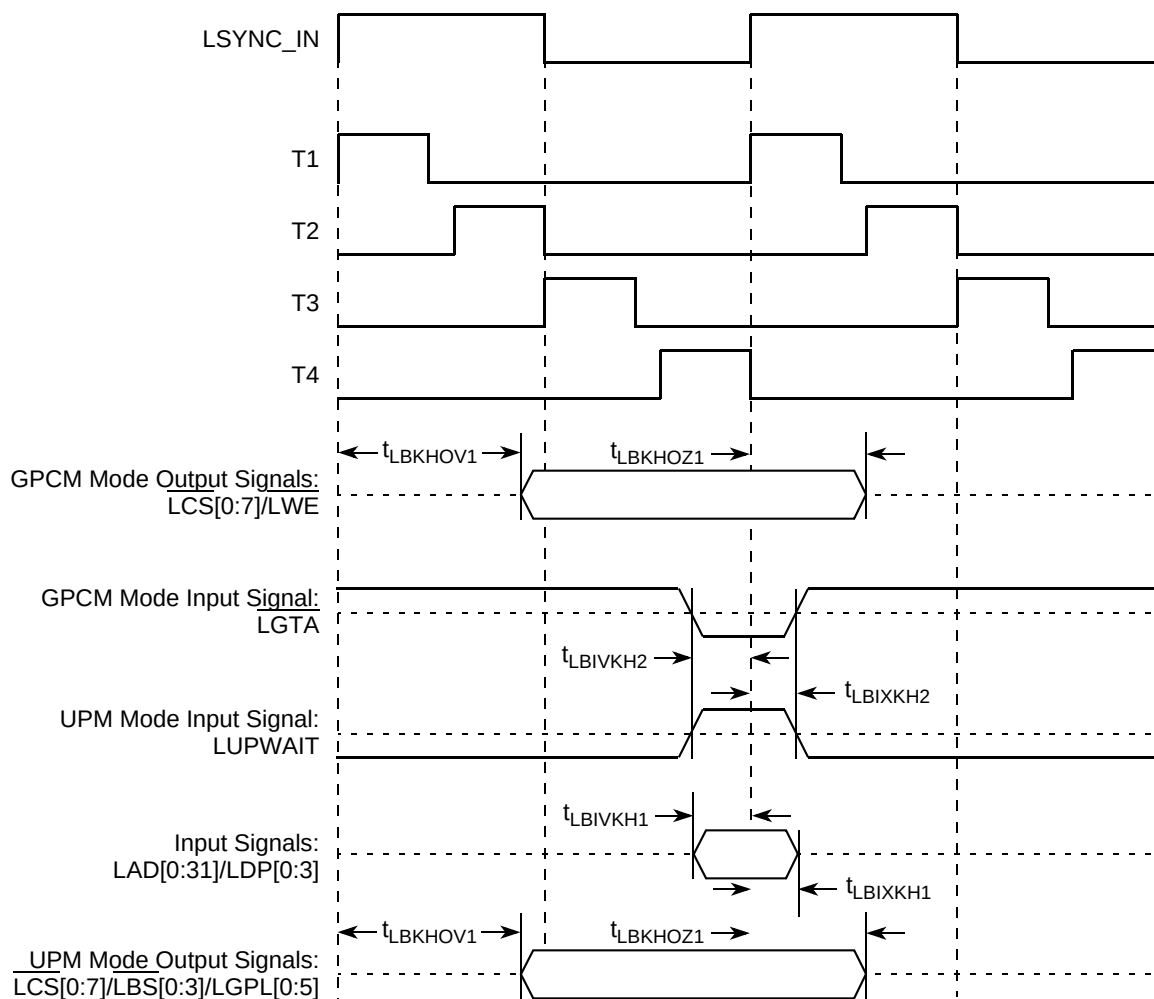


Figure 27. Local Bus Signals, GPCM/UPM Signals for LCCR[CLKDIV] = 8 or 16 (PLL Enabled)

13 I²C

This section describes the DC and AC electrical characteristics for the I²C interfaces of the device.

13.1 I²C DC Electrical Characteristics

This table provides the DC electrical characteristics for the I²C interfaces.

Table 45. I²C DC Electrical Characteristics

Parameter	Symbol	Min	Max	Unit	Notes
Input high voltage level	V _{IH}	0.7 × OV _{DD}	OV _{DD} + 0.3	V	—
Input low voltage level	V _{IL}	−0.3	0.3 × OV _{DD}	V	—
Low level output voltage	V _{OL}	0	0.2 × OV _{DD}	V	1
Pulse width of spikes which must be suppressed by the input filter	t _{I2KHKL}	0	50	ns	2
Input current each I/O pin (input voltage is between 0.1 × OV _{DD} and 0.9 × OV _{DD} (max))	I _I	−10	10	μA	3
Capacitance for each I/O pin	C _I	—	10	pF	—

Notes:

1. Output voltage (open drain or open collector) condition = 3 mA sink current.
2. See the *MPC8548E PowerQUICC™ III Integrated Processor Family Reference Manual*, for information on the digital filter used.
3. I/O pins obstruct the SDA and SCL lines if OV_{DD} is switched off.

13.2 I²C AC Electrical Specifications

This table provides the AC timing parameters for the I²C interfaces.

Table 46. I²C AC Electrical Specifications

Parameter	Symbol ¹	Min	Max	Unit	Notes
SCL clock frequency	f _{I2C}	0	400	kHz	—
Low period of the SCL clock	t _{I2CL}	1.3	—	μs	4
High period of the SCL clock	t _{I2CH}	0.6	—	μs	4
Setup time for a repeated START condition	t _{I2SVKH}	0.6	—	μs	4
Hold time (repeated) START condition (after this period, the first clock pulse is generated)	t _{I2SXKL}	0.6	—	μs	4
Data setup time	t _{I2DVKH}	100	—	ns	4
Data input hold time: CBUS compatible masters I ² C bus devices	t _{I2DXKL}	— 0	— —	μs	2
Data output delay time:	t _{I2OVKL}	—	0.9	—	3
Set-up time for STOP condition	t _{I2PVKH}	0.6	—	μs	—
Bus free time between a STOP and START condition	t _{I2KHDX}	1.3	—	μs	—

16.2.4 AC Requirements for SerDes Reference Clocks

The clock driver selected must provide a high quality reference clock with low phase noise and cycle-to-cycle jitter. Phase noise less than 100 kHz can be tracked by the PLL and data recovery loops and is less of a problem. Phase noise above 15 MHz is filtered by the PLL. The most problematic phase noise occurs in the 1–15 MHz range. The source impedance of the clock driver must be $50\ \Omega$ to match the transmission line and reduce reflections which are a source of noise to the system.

The detailed AC requirements of the SerDes reference clocks are defined by each interface protocol based on application usage. See the following sections for detailed information:

- [Section 17.2, “AC Requirements for PCI Express SerDes Clocks”](#)
- [Section 18.2, “AC Requirements for Serial RapidIO SD_REF_CLK and SD_REF_CLK”](#)

16.2.4.1 Spread Spectrum Clock

SD_REF_CLK/SD_REF_CLK are designed to work with a spread spectrum clock (+0% to –0.5% spreading at 30–33 kHz rate is allowed), assuming both ends have same reference clock. For better results, a source without significant unintended modulation must be used.

16.3 SerDes Transmitter and Receiver Reference Circuits

Figure 47 shows the reference circuits for SerDes data lane’s transmitter and receiver.

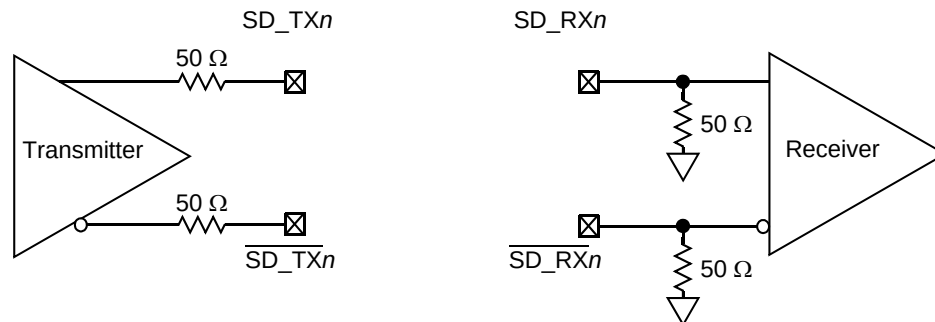


Figure 47. SerDes Transmitter and Receiver Reference Circuits

The DC and AC specification of SerDes data lanes are defined in each interface protocol section below (PCI Express, Serial Rapid IO, or SGMII) in this document based on the application usage:

- [Section 17, “PCI Express”](#)
- [Section 18, “Serial RapidIO”](#)

Note that external an AC coupling capacitor is required for the above three serial transmission protocols with the capacitor value defined in the specification of each protocol section.

17 PCI Express

This section describes the DC and AC electrical specifications for the PCI Express bus of the MPC8548E.

17.1 DC Requirements for PCI Express SD_REF_CLK and SD_REF_CLK

For more information, see [Section 16.2, “SerDes Reference Clocks.”](#)

17.2 AC Requirements for PCI Express SerDes Clocks

[Table 55](#) lists the AC requirements for the PCI Express SerDes clocks.

Table 55. SD_REF_CLK and SD_REF_CLK AC Requirements

Symbol	Parameter Description	Min	Typ	Max	Unit	Notes
t_{REF}	REFCLK cycle time	—	10	—	ns	1
t_{REFCJ}	REFCLK cycle-to-cycle jitter. Difference in the period of any two adjacent REFCLK cycles.	—	—	100	ps	—
t_{REFPJ}	Phase jitter. Deviation in edge location with respect to mean edge location.	–50	—	50	ps	—

Note:

1. Typical based on *PCI Express Specification 2.0*.

17.3 Clocking Dependencies

The ports on the two ends of a link must transmit data at a rate that is within 600 parts per million (ppm) of each other at all times. This is specified to allow bit rate clock sources with a ± 300 ppm tolerance.

17.4 Physical Layer Specifications

The following is a summary of the specifications for the physical layer of PCI Express on this device. For further details as well as the specifications of the transport and data link layer see *PCI Express Base Specification, Rev. 1.0a*.

17.4.1 Differential Transmitter (TX) Output

[Table 56](#) defines the specifications for the differential output at all transmitters (TXs). The parameters are specified at the component pins.

Table 57. Differential Receiver (RX) Input Specifications (continued)

Symbol	Parameter	Min	Nom	Max	Unit	Comments
$L_{TX-SKEW}$	Total Skew	—	—	20	ns	Skew across all lanes on a Link. This includes variation in the length of SKP ordered set (for example, COM and one to five symbols) at the RX as well as any delay differences arising from the interconnect itself.

Notes:

1. No test load is necessarily associated with this value.
2. Specified at the measurement point and measured over any 250 consecutive UIs. The test load in [Figure 50](#) must be used as the RX device when taking measurements (also see the receiver compliance eye diagram shown in [Figure 49](#)). If the clocks to the RX and TX are not derived from the same reference clock, the TX UI recovered from 3500 consecutive UI must be used as a reference for the eye diagram.
3. A $T_{RX-EYE} = 0.40$ UI provides for a total sum of 0.60 UI deterministic and random jitter budget for the transmitter and interconnect collected any 250 consecutive UIs. The $T_{RX-EYE-MEDIAN-to-MAX-JITTER}$ specification ensures a jitter distribution in which the median and the maximum deviation from the median is less than half of the total. UI jitter budget collected over any 250 consecutive TX UIs. Note that the median is not the same as the mean. The jitter median describes the point in time where the number of jitter points on either side is approximately equal as opposed to the averaged time value. If the clocks to the RX and TX are not derived from the same reference clock, the TX UI recovered from 3500 consecutive UI must be used as the reference for the eye diagram.
4. The receiver input impedance shall result in a differential return loss greater than or equal to 15 dB with the D+ line biased to 300 mV and the D– line biased to –300 mV and a common mode return loss greater than or equal to 6 dB (no bias required) over a frequency range of 50 MHz to 1.25 GHz. This input impedance requirement applies to all valid input levels. The reference impedance for return loss measurements for is 50 Ω to ground for both the D+ and D– line (that is, as measured by a vector network analyzer with 50- Ω probes—see [Figure 50](#)). Note: that the series capacitors CTX is optional for the return loss measurement.
5. Impedance during all LTSSM states. When transitioning from a fundamental reset to detect (the initial state of the LTSSM) there is a 5 ms transition time before receiver termination values must be met on all unconfigured lanes of a port.
6. The RX DC common mode Impedance that exists when no power is present or fundamental reset is asserted. This helps ensure that the receiver detect circuit does not falsely assume a receiver is powered on when it is not. This term must be measured at 300 mV above the RX ground.
7. It is recommended that the recovered TX UI is calculated using all edges in the 3500 consecutive UI interval with a fit algorithm using a minimization merit function. Least squares and median deviation fits have worked well with experimental and simulated data.

17.5 Receiver Compliance Eye Diagrams

The RX eye diagram in [Figure 49](#) is specified using the passive compliance/test measurement load (see [Figure 50](#)) in place of any real PCI Express RX component.

Note: In general, the minimum receiver eye diagram measured with the compliance/test measurement load (see [Figure 50](#)) is larger than the minimum receiver eye diagram measured over a range of systems at the input receiver of any real PCI Express component. The degraded eye diagram at the input receiver is due to traces internal to the package as well as silicon parasitic characteristics which cause the real PCI Express component to vary in impedance from the compliance/test measurement load. The input receiver eye diagram is implementation specific and is not specified. RX component designer must provide additional margin to adequately compensate for the degraded minimum receiver eye diagram (shown in [Figure 49](#)) expected at the input receiver based on some adequate combination of system simulations and the return loss measured looking into the RX package and silicon. The RX eye diagram must be aligned in time using the jitter median to locate the center of the eye diagram.

The eye diagram must be valid for any 250 consecutive UIs.

A recovered TX UI is calculated over 3500 consecutive unit intervals of sample data. The eye diagram is created using all edges of the 250 consecutive UI in the center of the 3500 UI used for calculating the TX UI.

NOTE

The reference impedance for return loss measurements is 50. to ground for both the D+ and D– line (that is, as measured by a vector network analyzer with 50-Ω probes—see [Figure 50](#)). Note that the series capacitors, CTX, are optional for the return loss measurement.

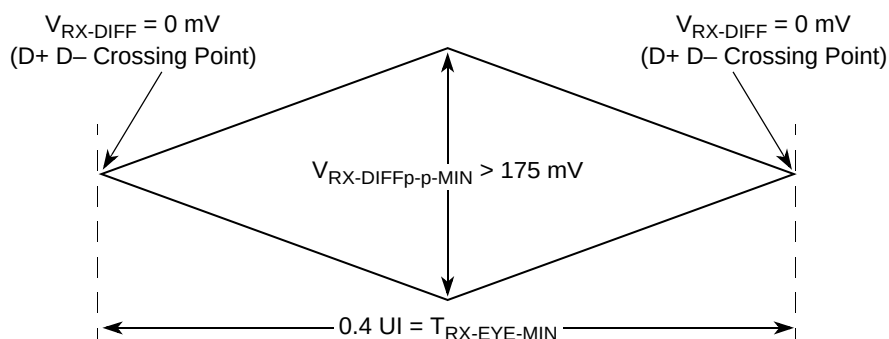


Figure 49. Minimum Receiver Eye Timing and Voltage Compliance Specification

17.5.1 Compliance Test and Measurement Load

The AC timing and voltage parameters must be verified at the measurement point, as specified within 0.2 inches of the package pins, into a test/measurement load shown in [Figure 50](#).

NOTE

The allowance of the measurement point to be within 0.2 inches of the package pins is meant to acknowledge that package/board routing may benefit from D+ and D– not being exactly matched in length at the package pin boundary.

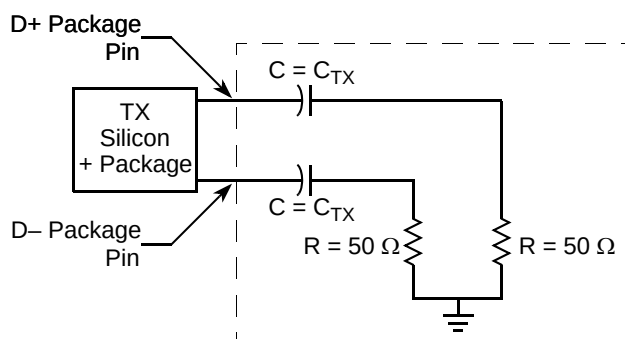


Figure 50. Compliance Test/Measurement Load

Table 63. Long Run Transmitter AC Timing Specifications—2.5 GBaud

Characteristic	Symbol	Range		Unit	Notes
		Min	Max		
Output voltage	V_O	-0.40	2.30	V	Voltage relative to COMMON of either signal comprising a differential pair
Differential output voltage	V_{DIFFPP}	800	1600	mVp-p	—
Deterministic jitter	J_D	—	0.17	UI p-p	—
Total jitter	J_T	—	0.35	UI p-p	—
Multiple output skew	S_{MO}	—	1000	ps	Skew at the transmitter output between lanes of a multilane link
Unit interval	UI	400	400	ps	±100 ppm

Table 64. Long Run Transmitter AC Timing Specifications—3.125 GBaud

Characteristic	Symbol	Range		Unit	Notes
		Min	Max		
Output voltage	V_O	-0.40	2.30	V	Voltage relative to COMMON of either signal comprising a differential pair
Differential output voltage	V_{DIFFPP}	800	1600	mVp-p	—
Deterministic jitter	J_D	—	0.17	UI p-p	—
Total jitter	J_T	—	0.35	UI p-p	—
Multiple output skew	S_{MO}	—	1000	ps	Skew at the transmitter output between lanes of a multilane link
Unit interval	UI	320	320	ps	±100 ppm

For each baud rate at which an LP-serial transmitter is specified to operate, the output eye pattern of the transmitter shall fall entirely within the unshaded portion of the transmitter output compliance mask shown in [Figure 52](#) with the parameters specified in [Table 65](#) when measured at the output pins of the device and the device is driving a $100\text{-}\Omega \pm 5\%$ differential resistive load. The output eye pattern of an LP-serial

components are included in this requirement. The reference impedance for return loss measurements is 100- Ω resistive for differential return loss and 25- Ω resistive for common mode.

Table 66. Receiver AC Timing Specifications—1.25 GBaud

Characteristic	Symbol	Range		Unit	Notes
		Min	Max		
Differential input voltage	V_{IN}	200	1600	mVp-p	Measured at receiver
Deterministic jitter tolerance	J_D	0.37	—	UI p-p	Measured at receiver
Combined deterministic and random jitter tolerance	J_{DR}	0.55	—	UI p-p	Measured at receiver
Total jitter tolerance ¹	J_T	0.65	—	UI p-p	Measured at receiver
Multiple input skew	S_{MI}	—	24	ns	Skew at the receiver input between lanes of a multilane link
Bit error rate	BER	—	10^{-12}	—	—
Unit interval	UI	800	800	ps	± 100 ppm

Note:

1. Total jitter is composed of three components, deterministic jitter, random jitter, and single frequency sinusoidal jitter. The sinusoidal jitter may have any amplitude and frequency in the unshaded region of [Figure 53](#). The sinusoidal jitter component is included to ensure margin for low frequency jitter, wander, noise, crosstalk, and other variable system effects.

Table 67. Receiver AC Timing Specifications—2.5 GBaud

Characteristic	Symbol	Range		Unit	Notes
		Min	Max		
Differential input voltage	V_{IN}	200	1600	mVp-p	Measured at receiver
Deterministic jitter tolerance	J_D	0.37	—	UI p-p	Measured at receiver
Combined deterministic and random jitter tolerance	J_{DR}	0.55	—	UI p-p	Measured at receiver
Total jitter tolerance ¹	J_T	0.65	—	UI p-p	Measured at receiver
Multiple input skew	S_{MI}	—	24	ns	Skew at the receiver input between lanes of a multilane link
Bit error rate	BER	—	10^{-12}	—	—
Unit interval	UI	400	400	ps	± 100 ppm

Note:

1. Total jitter is composed of three components, deterministic jitter, random jitter, and single frequency sinusoidal jitter. The sinusoidal jitter may have any amplitude and frequency in the unshaded region of [Figure 53](#). The sinusoidal jitter component is included to ensure margin for low frequency jitter, wander, noise, crosstalk, and other variable system effects.

19 Package Description

This section details package parameters, pin assignments, and dimensions.

19.1 Package Parameters

The package parameters for both the HiCTE FC-CBGA and FC-PBGA are provided in [Table 70](#).

Table 70. Package Parameters

Parameter	CBGA ¹	PBGA ²
Package outline	29 mm × 29 mm	29 mm × 29 mm
Interconnects	783	783
Ball pitch	1 mm	1 mm
Ball diameter (typical)	0.6 mm	0.6 mm
Solder ball	63% Sn 37% Pb 0% Ag	63% Sn 37% Pb 0% Ag
Solder ball (lead-free)	95% Sn 4.5% Ag 0.5% Cu	96.5% Sn 3.5% Ag

Notes:

1. The HiCTE FC-CBGA package is available on only Version 2.0 of the device.
2. The FC-PBGA package is available on only versions 2.1.1 and 2.1.2, and 3.0 of the device.

Table 71. MPC8548E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
$\overline{\text{MWE}}$	E7	O	GV _{DD}	—
$\overline{\text{MCAS}}$	H7	O	GV _{DD}	—
$\overline{\text{MRAS}}$	L8	O	GV _{DD}	—
MCKE[0:3]	F10, C10, J11, H11	O	GV _{DD}	11
$\overline{\text{MCS}}[0:3]$	K8, J8, G8, F8	O	GV _{DD}	—
MCK[0:5]	H9, B15, G2, M9, A14, F1	O	GV _{DD}	—
$\overline{\text{MCK}}[0:5]$	J9, A15, G1, L9, B14, F2	O	GV _{DD}	—
MODT[0:3]	E6, K6, L7, M7	O	GV _{DD}	—
MDIC[0:1]	A19, B19	I/O	GV _{DD}	36
Local Bus Controller Interface				
LAD[0:31]	E27, B20, H19, F25, A20, C19, E28, J23, A25, K22, B28, D27, D19, J22, K20, D28, D25, B25, E22, F22, F21, C25, C22, B23, F20, A23, A22, E19, A21, D21, F19, B21	I/O	BV _{DD}	—
LDP[0:3]	K21, C28, B26, B22	I/O	BV _{DD}	—
LA[27]	H21	O	BV _{DD}	5, 9
LA[28:31]	H20, A27, D26, A28	O	BV _{DD}	5, 7, 9
$\overline{\text{LCS}}[0:4]$	J25, C20, J24, G26, A26	O	BV _{DD}	
$\overline{\text{LCS5/DMA_DREQ2}}$	D23	I/O	BV _{DD}	1
$\overline{\text{LCS6/DMA_DACK2}}$	G20	O	BV _{DD}	1
$\overline{\text{LCS7/DMA_DDONE2}}$	E21	O	BV _{DD}	1
$\overline{\text{LWE0/LBS0/LSDDQM}}[0]$	G25	O	BV _{DD}	5, 9
$\overline{\text{LWE1/LBS1/LSDDQM}}[1]$	C23	O	BV _{DD}	5, 9
$\overline{\text{LWE2/LBS2/LSDDQM}}[2]$	J21	O	BV _{DD}	5, 9
$\overline{\text{LWE3/LBS3/LSDDQM}}[3]$	A24	O	BV _{DD}	5, 9
LALE	H24	O	BV _{DD}	5, 8, 9
LBCTL	G27	O	BV _{DD}	5, 8, 9
LGPL0/LSDA10	F23	O	BV _{DD}	5, 9
LGPL1/LSDWE	G22	O	BV _{DD}	5, 9
LGPL2/ $\overline{\text{LOE/LSDRAS}}$	B27	O	BV _{DD}	5, 8, 9
LGPL3/ $\overline{\text{LSDCAS}}$	F24	O	BV _{DD}	5, 9
LGPL4/ $\overline{\text{LGT\AA/LUPWAIT/LPBSE}}$	H23	I/O	BV _{DD}	—
LGPL5	E26	O	BV _{DD}	5, 9
LCKE	E24	O	BV _{DD}	—
LCLK[0:2]	E23, D24, H22	O	BV _{DD}	—

Table 71. MPC8548E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
Three-Speed Ethernet Controller (Gigabit Ethernet 2)				
TSEC2_RXD[7:0]	P2, R2, N1, N2, P3, M2, M1, N3	I	LV _{DD}	—
TSEC2_TXD[7:0]	N9, N10, P8, N7, R9, N5, R8, N6	O	LV _{DD}	5, 9, 33
TSEC2_COL	P1	I	LV _{DD}	—
TSEC2_CRS	R6	I/O	LV _{DD}	20
TSEC2_GTX_CLK	P6	O	LV _{DD}	
TSEC2_RX_CLK	N4	I	LV _{DD}	—
TSEC2_RX_DV	P5	I	LV _{DD}	—
TSEC2_RX_ER	R1	I	LV _{DD}	—
TSEC2_TX_CLK	P10	I	LV _{DD}	—
TSEC2_TX_EN	P7	O	LV _{DD}	30
TSEC2_TX_ER	R10	O	LV _{DD}	5, 9, 33
Three-Speed Ethernet Controller (Gigabit Ethernet 3)				
TSEC3_TXD[3:0]	V8, W10, Y10, W7	O	TV _{DD}	5, 9, 29
TSEC3_RXD[3:0]	Y1, W3, W5, W4	I	TV _{DD}	—
TSEC3_GTX_CLK	W8	O	TV _{DD}	—
TSEC3_RX_CLK	W2	I	TV _{DD}	—
TSEC3_RX_DV	W1	I	TV _{DD}	—
TSEC3_RX_ER	Y2	I	TV _{DD}	—
TSEC3_TX_CLK	V10	I	TV _{DD}	—
TSEC3_TX_EN	V9	O	TV _{DD}	30
Three-Speed Ethernet Controller (Gigabit Ethernet 4)				
TSEC4_TXD[3:0]/TSEC3_TXD[7:4]	AB8, Y7, AA7, Y8	O	TV _{DD}	1, 5, 9, 29
TSEC4_RXD[3:0]/TSEC3_RXD[7:4]	AA1, Y3, AA2, AA4	I	TV _{DD}	1
TSEC4_GTX_CLK	AA5	O	TV _{DD}	—
TSEC4_RX_CLK/TSEC3_COL	Y5	I	TV _{DD}	1
TSEC4_RX_DV/TSEC3_CRS	AA3	I/O	TV _{DD}	1, 31
TSEC4_TX_EN/TSEC3_TX_ER	AB6	O	TV _{DD}	1, 30
DUART				
UART_CTS[0:1]	AB3, AC5	I	OV _{DD}	—
UART_RTS[0:1]	AC6, AD7	O	OV _{DD}	—
UART_SIN[0:1]	AB5, AC7	I	OV _{DD}	—
UART_SOUT[0:1]	AB7, AD8	O	OV _{DD}	—

Table 71. MPC8548E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
SENSEVSS	M16	—	—	13
Analog Signals				
MVREF	A18	I Reference voltage signal for DDR	MVREF	—
SD_IMP_CAL_RX	L28	I	200Ω to GND	—
SD_IMP_CAL_TX	AB26	I	100Ω to GND	—
SD_PLL_TPA	U26	O	—	24

Notes:

1. All multiplexed signals are listed only once and do not re-occur. For example, $\overline{\text{LCS5/DMA_REQ2}}$ is listed only once in the local bus controller section, and is not mentioned in the DMA section even though the pin also functions as $\overline{\text{DMA_REQ2}}$.
2. Recommend a weak pull-up resistor (2–10 kΩ) be placed on this pin to OV_{DD} .
3. A valid clock must be provided at POR if $\text{TSEC4_TXD}[2]$ is set = 1.
4. This pin is an open drain signal.
5. This pin is a reset configuration pin. It has a weak internal pull-up P-FET which is enabled only when the processor is in the reset state. This pull-up is designed such that it can be overpowered by an external 4.7-kΩ pull-down resistor. However, if the signal is intended to be high after reset, and if there is any device on the net which might pull down the value of the net at reset, then a pull-up or active driver is needed.
6. Treat these pins as no connects (NC) unless using debug address functionality.
7. The value of $\text{LA}[28:31]$ during reset sets the CCB clock to SYSCLK PLL ratio. These pins require 4.7-kΩ pull-up or pull-down resistors. See [Section 20.2, "CCB/SYSCLK PLL Ratio."](#)
8. The value of LALE , LGPL2 , and LBCTL at reset set the e500 core clock to CCB clock PLL ratio. These pins require 4.7-kΩ pull-up or pull-down resistors. See the [Section 20.3, "e500 Core PLL Ratio."](#)
9. Functionally, this pin is an output, but structurally it is an I/O because it either samples configuration input during reset or because it has other manufacturing test functions. This pin therefore is described as an I/O for boundary scan.
10. This pin functionally requires a pull-up resistor, but during reset it is a configuration input that controls 32- vs. 64-bit PCI operation. Therefore, it must be actively driven low during reset by reset logic if the device is to be configured to be a 64-bit PCI device. See the *PCI Specification*.
11. This output is actively driven during reset rather than being three-stated during reset.
12. These JTAG pins have weak internal pull-up P-FETs that are always enabled.
13. These pins are connected to the $\text{V}_{\text{DD}}/\text{GND}$ planes internally and may be used by the core power supply to improve tracking and regulation.
14. Internal thermally sensitive resistor.
15. No connections must be made to these pins if they are not used.
16. These pins are not connected for any use.
17. PCI specifications recommend that a weak pull-up resistor (2–10 kΩ) be placed on the higher order pins to OV_{DD} when using 64-bit buffer mode (pins $\text{PCI_AD}[63:32]$ and $\text{PCI1_C_BE}[7:4]$).
19. If this pin is connected to a device that pulls down during reset, an external pull-up is required to drive this pin to a safe state during reset.
20. This pin is only an output in FIFO mode when used as Rx flow control.
24. Do not connect.

Table 72 provides the pin-out listing for the MPC8547E 783 FC-PBGA package.

NOTE

All note references in the following table use the same numbers as those for Table 71. See Table 71 for the meanings of these notes.

Table 72. MPC8547E Pinout Listing

Signal	Package Pin Number	Pin Type	Power Supply	Notes
PCI1 (One 64-Bit or One 32-Bit)				
PCI1_AD[63:32]	AB14, AC15, AA15, Y16, W16, AB16, AC16, AA16, AE17, AA18, W18, AC17, AD16, AE16, Y17, AC18, AB18, AA19, AB19, AB21, AA20, AC20, AB20, AB22, AC22, AD21, AB23, AF23, AD23, AE23, AC23, AC24	I/O	OV _{DD}	17
PCI1_AD[31:0]	AH6, AE7, AF7, AG7, AH7, AF8, AH8, AE9, AH9, AC10, AB10, AD10, AG10, AA10, AH10, AA11, AB12, AE12, AG12, AH12, AB13, AA12, AC13, AE13, Y14, W13, AG13, V14, AH13, AC14, Y15, AB15	I/O	OV _{DD}	17
PCI1_C_BE[7:4]	AF15, AD14, AE15, AD15	I/O	OV _{DD}	17
PCI1_C_BE[3:0]	AF9, AD11, Y12, Y13	I/O	OV _{DD}	17
PCI1_PAR64	W15	I/O	OV _{DD}	—
PCI1_GNT[4:1]	AG6, AE6, AF5, AH5	O	OV _{DD}	5, 9, 35
PCI1_GNT0	AG5	I/O	OV _{DD}	—
PCI1_IRDY	AF11	I/O	OV _{DD}	2
PCI1_PAR	AD12	I/O	OV _{DD}	—
PCI1_PERR	AC12	I/O	OV _{DD}	2
PCI1_SERR	V13	I/O	OV _{DD}	2, 4
PCI1_STOP	W12	I/O	OV _{DD}	2
PCI1_TRDY	AG11	I/O	OV _{DD}	2
PCI1_REQ[4:1]	AH2, AG4, AG3, AH4	I	OV _{DD}	—
PCI1_REQ0	AH3	I/O	OV _{DD}	—
PCI1_CLK	AH26	I	OV _{DD}	39
PCI1_DEVSEL	AH11	I/O	OV _{DD}	2
PCI1_FRAME	AE11	I/O	OV _{DD}	2
PCI1_IDSEL	AG9	I	OV _{DD}	—
PCI1_REQ64	AF14	I/O	OV _{DD}	2, 5, 10
PCI1_ACK64	V15	I/O	OV _{DD}	2
Reserved	AE28	—	—	2
Reserved	AD26	—	—	2
Reserved	AD25	—	—	2

Table 72. MPC8547E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
DFT				
L1_TSTCLK	AC25	I	OV _{DD}	25
L2_TSTCLK	AE22	I	OV _{DD}	25
$\overline{\text{LSSD_MODE}}$	AH20	I	OV _{DD}	25
$\overline{\text{TEST_SEL}}$	AH14	I	OV _{DD}	25
Thermal Management				
THERM0	AG1	—	—	14
THERM1	AH1	—	—	14
Power Management				
ASLEEP	AH18	O	OV _{DD}	9, 19, 29
Power and Ground Signals				
GND	A11, B7, B24, C1, C3, C5, C12, C15, C26, D8, D11, D16, D20, D22, E1, E5, E9, E12, E15, E17, F4, F26, G12, G15, G18, G21, G24, H2, H6, H8, H28, J4, J12, J15, J17, J27, K7, K9, K11, K27, L3, L5, L12, L16, N11, N13, N15, N17, N19, P4, P9, P12, P14, P16, P18, R11, R13, R15, R17, R19, T4, T12, T14, T16, T18, U8, U11, U13, U15, U17, U19, V4, V12, V18, W6, W19, Y4, Y9, Y11, Y19, AA6, AA14, AA17, AA22, AA23, AB4, AC2, AC11, AC19, AC26, AD5, AD9, AD22, AE3, AE14, AF6, AF10, AF13, AG8, AG27, K28, L24, L26, N24, N27, P25, R28, T24, T26, U24, V25, W28, Y24, Y26, AA24, AA27, AB25, AC28, L21, L23, N22, P20, R23, T21, U22, V20, W23, Y21, U27	—	—	—
OV _{DD}	V16, W11, W14, Y18, AA13, AA21, AB11, AB17, AB24, AC4, AC9, AC21, AD6, AD13, AD17, AD19, AE10, AE8, AE24, AF4, AF12, AF22, AF27, AG26	Power for PCI and other standards (3.3 V)	OV _{DD}	—
LV _{DD}	N8, R7, T9, U6	Power for TSEC1 and TSEC2 (2.5 V, 3.3 V)	LV _{DD}	—
TV _{DD}	W9, Y6	Power for TSEC3 and TSEC4 (2.5 V, 3.3 V)	TV _{DD}	—
GV _{DD}	B3, B11, C7, C9, C14, C17, D4, D6, D10, D15, E2, E8, E11, E18, F5, F12, F16, G3, G7, G9, G11, H5, H12, H15, H17, J10, K3, K12, K16, K18, L6, M4, M8, M13	Power for DDR1 and DDR2 DRAM I/O voltage (1.8 V, 2.5 V)	GV _{DD}	—

Table 73. MPC8545E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
$\overline{\text{UDE}}$	AH16	I	OV _{DD}	—
$\overline{\text{MCP}}$	AG19	I	OV _{DD}	—
IRQ[0:7]	AG23, AF18, AE18, AF20, AG18, AF17, AH24, AE20	I	OV _{DD}	—
IRQ[8]	AF19	I	OV _{DD}	—
IRQ[9]/DMA_DREQ3	AF21	I	OV _{DD}	1
IRQ[10]/DMA_DACK3	AE19	I/O	OV _{DD}	1
IRQ[11]/DMA_DDONE3	AD20	I/O	OV _{DD}	1
$\overline{\text{IRQ_OUT}}$	AD18	O	OV _{DD}	2, 4
Ethernet Management Interface				
EC_MDC	AB9	O	OV _{DD}	5, 9
EC_MDIO	AC8	I/O	OV _{DD}	—
Gigabit Reference Clock				
EC_GTX_CLK125	V11	I	LV _{DD}	—
Three-Speed Ethernet Controller (Gigabit Ethernet 1)				
TSEC1_RXD[7:0]	R5, U1, R3, U2, V3, V1, T3, T2	I	LV _{DD}	—
TSEC1_TXD[7:0]	T10, V7, U10, U5, U4, V6, T5, T8	O	LV _{DD}	5, 9
TSEC1_COL	R4	I	LV _{DD}	—
TSEC1_CRS	V5	I/O	LV _{DD}	20
TSEC1_GTX_CLK	U7	O	LV _{DD}	—
TSEC1_RX_CLK	U3	I	LV _{DD}	—
TSEC1_RX_DV	V2	I	LV _{DD}	—
TSEC1_RX_ER	T1	I	LV _{DD}	—
TSEC1_TX_CLK	T6	I	LV _{DD}	—
TSEC1_TX_EN	U9	O	LV _{DD}	30
TSEC1_TX_ER	T7	O	LV _{DD}	—
GPIN[0:7]	P2, R2, N1, N2, P3, M2, M1, N3	I	LV _{DD}	103
GPOUT[0:5]	N9, N10, P8, N7, R9, N5	O	LV _{DD}	—
cfg_dram_type0/GPOUT6	R8	O	LV _{DD}	5, 9
GPOUT7	N6	O	LV _{DD}	—
Reserved	P1	—	—	104
Reserved	R6	—	—	104
Reserved	P6	—	—	15
Reserved	N4	—	—	105